

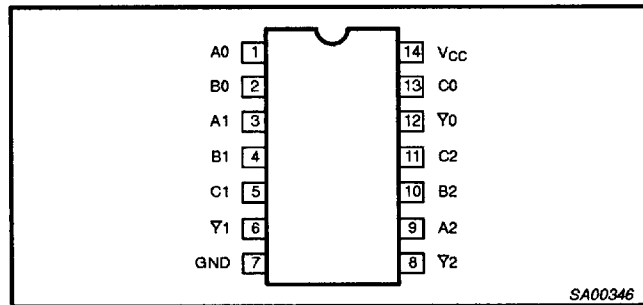
3.3V Triple 3-input NAND gate

74LVT10

QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^{\circ}\text{C};$ $GND = 0V$	TYPICAL	UNIT
t_{PLH} t_{PHL}	Propagation delay A_n, B_n, C_n to \bar{Y}_n	$C_L = 50\text{pF};$ $V_{CC} = 3.3V$	3.8 3.3	ns
C_{IN}	Input capacitance	$V_I = 0V$ or $3.0V$	2	pF
I_{CCL}	Total supply current	Outputs Low; $V_{CC} = 3.6V$	1	mA

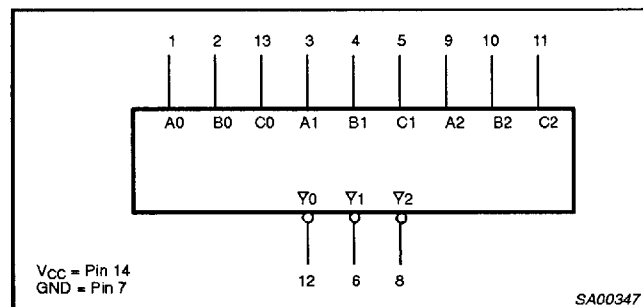
PIN CONFIGURATION



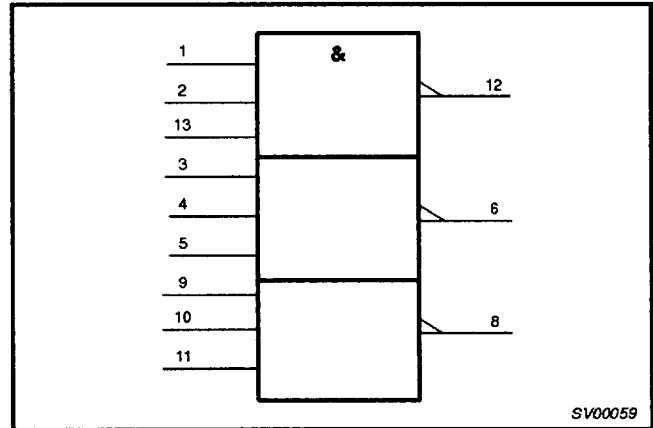
PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1, 2, 3, 4, 5, 9, 10, 11, 13	A_n, B_n, C_n	Data inputs
6, 8, 12	\bar{Y}_n	Data outputs
7	GND	Ground (0V)
14	V_{CC}	Positive supply voltage

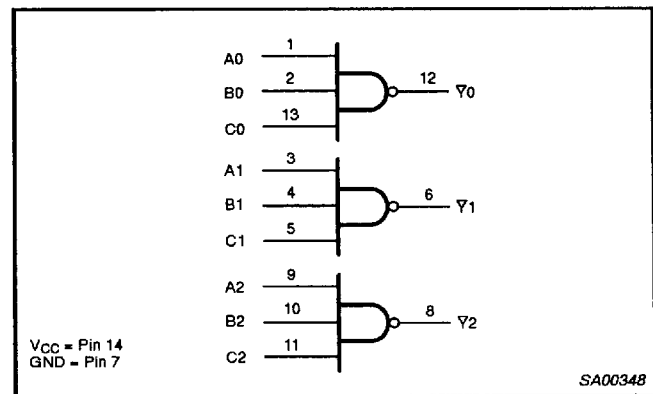
LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



LOGIC DIAGRAM



FUNCTION TABLE

INPUTS			OUTPUTS
D_{na}	D_{nb}	D_{nc}	\bar{Q}_n
L	L	L	H
L	L	H	H
L	H	L	H
L	H	H	H
H	L	L	H
H	L	H	H
H	H	L	H
H	H	H	L

NOTES:
H = High voltage level
L = Low voltage level

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
14-Pin Plastic SO	-40°C to +85°C	74LVT10 D	74LVT10 D	SOT108-1
14-Pin Plastic SSOP	-40°C to +85°C	74LVT10 DB	74LVT10 DB	SOT337-1
14-Pin Plastic TSSOP	-40°C to +85°C	74LVT10 PW	74LVT10PW DH	SOT402-1

7110826 0104694 680

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +4.6	V
I _{IK}	DC input diode current	V _I < 0	-50	mA
V _I	DC input voltage ³		-0.5 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	Output in Off or High state	-0.5 to +7.0	V
I _{OUT}	DC output current	Output in High state	-32	mA
		Output in Low state	64	
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		MIN	MAX	
V _{CC}	DC supply voltage	2.7	3.6	V
V _I	Input voltage	0	5.5	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level input voltage		0.8	V
I _{OH}	High-level output current		-20	mA
I _{OL}	Low-level output current		32	mA
Δt/Δv	Input transition rise or fall rate; Outputs enabled		10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

Over recommended operating conditions
 Voltages are referenced to GND (ground = 0V)

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			Temp = -40°C to +85°C			
			MIN	TYP ¹	MAX	
V_{IK}	Input clamp voltage	$V_{CC} = 2.7V; I_{IK} = -18mA$			-1.2	V
V_{OH}	High-level output voltage	$V_{CC} = 2.7 \text{ to } 3.6V; I_{OH} = -100\mu A$	$V_{CC}-0.2$	V_{CC}		V
		$V_{CC} = 2.7V; I_{OH} = -6mA$	2.4	2.5		
		$V_{CC} = 3.0V; I_{OH} = -20mA$	2.0	2.3		
V_{OL}	Low-level output voltage	$V_{CC} = 2.7V; I_{OL} = 100\mu A$		0.05	0.2	V
		$V_{CC} = 2.7V; I_{OL} = 24mA$		0.3	0.5	
		$V_{CC} = 3.0V; I_{OL} = 32mA$		0.35	0.5	
I_I	Input leakage current	$V_{CC} = 0 \text{ or } 3.6V; V_I = 5.5V$		0.1	10	μA
		$V_{CC} = 3.6V; V_I = V_{CC} \text{ or } GND$		0.01	± 1	
I_{OFF}	Output off current	$V_{CC} = 0V; V_I \text{ or } V_O = 0 \text{ to } 4.5V$		1	± 100	μA
I_{CCH}	Quiescent supply current	$V_{CC} = 3.6V; \text{Outputs High, } V_I = GND \text{ or } V_{CC}, I_O = 0$		0.001	0.02	mA
I_{CCL}		$V_{CC} = 3.6V; \text{Outputs Low, } V_I = GND \text{ or } V_{CC}, I_O = 0$		1	2	
ΔI_{CC}	Additional supply current per input pin ²	$V_{CC} = 3V \text{ to } 3.6V; \text{One input at } V_{CC}-0.6V, \text{Other inputs at } V_{CC} \text{ or } GND$		0.1	0.2	mA
C_I	Input capacitance	$V_I = 3V \text{ or } 0$		2		pF

NOTES:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^\circ C$.
2. This is the increase in supply current for each input at the specified voltage level other than V_{CC} or GND.

AC CHARACTERISTICS

$GND = 0V; t_{IR} = t_F = 2.5ns; C_L = 50pF, R_L = 500\Omega; T_{amb} = -40^\circ C \text{ to } +85^\circ C$.

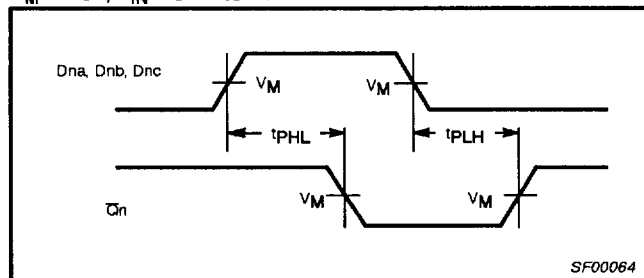
SYMBOL	PARAMETER	WAVEFORM	LIMITS				UNIT
			$V_{CC} = 3.3V \pm 0.3V$			$V_{CC} = 2.7V$	
			MIN	TYP ¹	MAX	MAX	
t_{PLH} t_{PHL}	Propagation delay An, Bn, Cn to Yn	1	1.0 1.0	3.8 3.3	5.2 4.4	6.2 4.4	ns

NOTE:

1. All typical values are at $V_{CC} = 3.3V$ and $T_{amb} = 25^\circ C$.

AC WAVEFORMS

$V_M = 1.5V, V_{IN} = GND \text{ to } 2.7V$

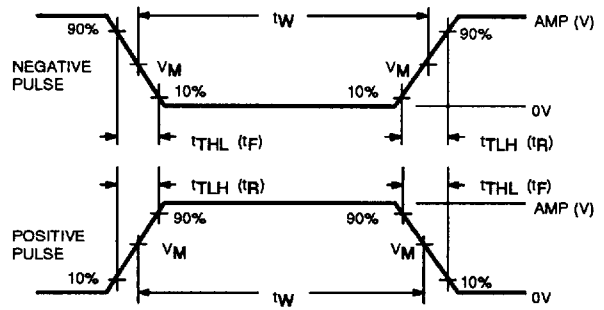
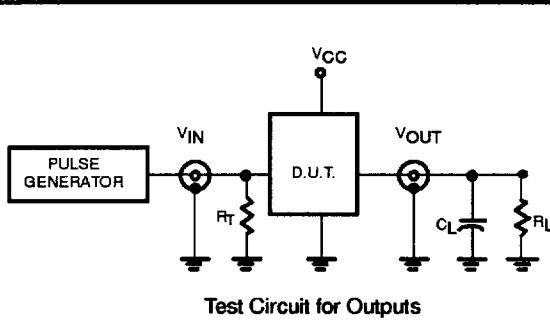


Waveform 1. Propagation Delay for Inverting Outputs

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TEST CIRCUIT AND WAVEFORMS



$V_M = 1.5V$
Input Pulse Definition

DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
- C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
- R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_w	t_R	t_F
74LVT	2.7V	$\leq 10MHz$	500ns	$\leq 2.5ns$	$\leq 2.5ns$

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